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## CoolMOS<sup>™</sup> Power MOSFET IXKC 40N60C in ISOPLUS220<sup>™</sup> Package

### **Electrically Isolated Back Surface**

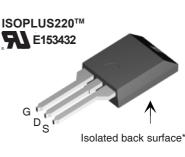
Low  $R_{DS(on)}$ , High Voltage, CoolMOS<sup>TM</sup> Superjunction MOSFET

Preliminary Data Sheet



Symbol	Test Conditions	Maximum Ratings			
V <sub>dss</sub>	$T_{J} = 25^{\circ}C \text{ to } 150^{\circ}C$	600	V		
V <sub>gs</sub>	Continuous	±20	V		
I <sub>D25</sub>	T <sub>c</sub> = 25°C; Note 1	28	А		
I <sub>D90</sub>	$T_c = 90^{\circ}C$ , Note 1	19	А		
I <sub>D(RMS)</sub>	Package lead current limit	45	Α		
E <sub>AS</sub> E <sub>AR</sub>	$I_{o} = 10A, T_{c} = 25^{\circ}C$ $I_{o} = 20A$	690 1	mJ mJ		
P <sub>D</sub>	$T_c = 25^{\circ}C$	250	W		
T		-55 +150	°C		
Т <sub>JM</sub>		150	°C		
T <sub>stg</sub>		-55 +125	°C		
T	1.6 mm (0.062 in.) from case for 10 s	300	°C		
V <sub>ISOL</sub>	RMS leads-to-tab, 50/60 Hz, t = 1 minute	2500	V~		
F <sub>c</sub>	Mounting force	11 65 / 2.411	N/lb		
Weight		3	g		

Symbol **Test Conditions Characteristic Values**  $(T_1 = 25^{\circ}C, unless otherwise specified)$ min. typ. max.  $\mathbf{R}_{\mathsf{DS(on)}}$ 96 mΩ  $V_{GS} = 10 \text{ V}, I_{D} = I_{D90}, \text{ Note 3}$ 80  $V_{gs} = 10 \text{ V}, I_{p} = I_{p90}, \text{ Note 3 } T_{J} = 125^{\circ}\text{C}$ 230 mΩ  $V_{DS} = V_{GS}, I_{D} = 2 \text{ mA}$ 3.5 5.5 V<sub>GS(th)</sub>  $\begin{array}{l} \mathsf{V}_{_{\mathrm{DS}}} = \mathsf{V}_{_{\mathrm{DSS}}} \\ \mathsf{V}_{_{\mathrm{GS}}} = 0 \ \mathsf{V} \end{array}$ T\_ = 25°C 2 I<sub>DSS</sub> T\_j = 125°C 20  $V_{GS} = \pm 20 V_{DC}, V_{DS} = 0$ +200I<sub>GSS</sub>



G = Gate, D = Drain, S = Source

\* Patent pending

**V**<sub>DSS</sub>

D25

 $\mathbf{R}_{\mathsf{DS(on)}}$ 

= 600

=

28

**96 m**Ω

V

#### **Features**

- Silicon chip on Direct-Copper-Bond substrate
  - High power dissipation
  - Isolated mounting surface
  - 2500V electrical isolation
- 3<sup>rd</sup> generation CoolMOS<sup>™</sup> power MOSFET - High blocking capability
- Low on resistance
- Avalanche rated for unclamped inductive switching (UIS)
- Low thermal resistance due to reduced chip thickness
- Low drain to tab capacitance(<30pF)</li>

#### Applications

- Switched Mode Power Supplies (SMPS)
- Uninterruptible Power Supplies (UPS)
- Power Factor Correction (PFC)
- Welding
- Inductive Heating

#### **Advantages**

V

μΑ

μA

nA

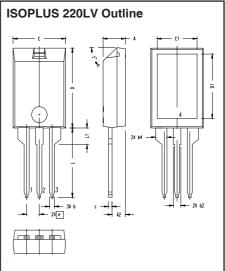
- · Easy assembly: no screws or isolation foils required
- Space savings
- High power density

CoolMOS is a trademark of Infineon Technolgies, AG

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### **IXKC 40N60C**

Symbol	Test Conditions	Cha (T <sub>J</sub> = 25°C, unless c <b>min.</b>		istic Va se spec max.	
<b>Q</b> <sub>g(on)</sub>			158		nC
<b>Q</b> <sub>gs</sub>	$V_{gs} = 10 \text{ V}, V_{ds} = 35$	0 V, I <sub>D</sub> = 40 A	42		nC
Q <sub>gd</sub>			92		nC
t <sub>d(on)</sub>			20		ns
t <sub>r</sub>	$V_{_{\rm GS}}$ = 10 V, $V_{_{\rm DS}}$ = 38	0V	55		ns
t <sub>d(off)</sub>	$I_{_{ m D}}$ = 40 A, $R_{_{ m G}}$ = 1.8 $\Omega$		60		ns
t,			10		ns
R <sub>thJC</sub>				0.5	K/W
R <sub>thCH</sub>			0.30		K/W



Reverse Correction		<b>Characteristic Values</b> $(T_1 = 25^{\circ}C, \text{ unless otherwise specified})$				
Symbol	Test Conditions			max.	ieu)	
V <sub>SD</sub>	$I_F = 20 \text{ A}, V_{GS} = 0 \text{ V}$ Note 3		0.8	1.2	V	

Note: 1. MOSFET chip capability

2. Intrinsic diode capability

3. Pulse test, t  $\leq$  300  $\mu s,$  duty cycle d  $\leq$  2 %

#### MILLIMETERS MIN MAX INCHES SYM MIN MAX 5.00 MAX .157 .197 4.00 Α 2.50 .118 .051 3.00 1.30 1.65 A2 .098 .035 b b2 .049 .065 1.25 .100 .039 2.35 b4 c .093 2.55 1.00 .028 15.00 12.00 10.00 16.00 13.00 D .591 .472 .630 .512 .433 D1 394 11.00 8.50 7.50 8.5 2.55 BASIC E1 .295 .335 100 BASIC е 571 13.00 3.00 512 14.50 3.50 L .118 .138 Ľ 42.5 47.5 Notes: 1. Lead 1 = Gate

2. Lead 2 = Drain

3. Lead 3 = Source

4. Back surface 4 is electrically

isolated from leads 1, 2 & 3

IXYS reserves the right to change limits, test conditions, and dimensions.